Power MOSFET

30 V, 1.7 m Ω , 159 A, Single N–Channel Logic Level, SO–8FL

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- NVMFS4C03NWF Wettable Flanks Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage		V_{DSS}	30	V	
Gate-to-Source Voltage	Gate-to-Source Voltage		V_{GS}	±20	V
Continuous Drain Current $R_{\theta JC}$ (Notes 1, 2, 3)			Ι _D	159	Α
Power Dissipation $R_{\theta JC}$ (Notes 1, 2)	Glate	T _C = 25°C	P _D	77	W
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2, 3)	- A = -		I _D	34.9	Α
Power Dissipation R _{θJA} (Notes 1, 2)	State	T _A = 25°C	P _D	3.71	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	900	Α
Operating Junction and Storage Temperature		T _J , T _{stg}	-55 to 175	ç	
Source Current (Body Diode)		I _S	64	Α	
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 11 A)		E _{AS}	549	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		T _L	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 2)	$R_{\theta JC}$	1.95	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	40	

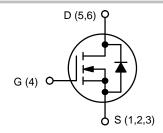
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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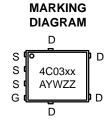
V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30 V	1.7 mΩ @ 10 V	450 4
30 V	2.4 mΩ @ 4.5 V	159 A



N-CHANNEL MOSFET



STYLE 1



4C03N = Specific Device Code for NVMFS4C03N

4C03WF= Specific Device Code of NVMFS4C03NWF

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NVMFS4C03NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C03NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel
NVMFS4C03NWFT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C03NWFT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

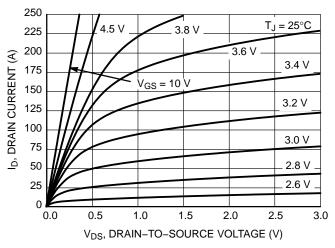
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•			
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D :	= 250 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				18.2		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{G}$	_S = 20 V			100	nA
ON CHARACTERISTICS (Note 4)					•		
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		1.3		2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		1.4	1.7	mΩ
		V _{GS} = 4.5 V	I _D = 30 A		2.0	2.4	
Forward Transconductance	9FS	V _{DS} = 3 V, I _D = 30 A			136		S
Gate Resistance	R_{G}	T _A = 25 °C			1.0		Ω
CHARGES AND CAPACITANCES					•		
Input Capacitance	C _{ISS}				3071		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1673		pF
Reverse Transfer Capacitance	C _{RSS}				67		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			20.8		- nC
Threshold Gate Charge	Q _{G(TH)}				4.9		
Gate-to-Source Charge	Q_{GS}				8.5		
Gate-to-Drain Charge	Q_{GD}				4.7		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 30 A			45.2		nC
SWITCHING CHARACTERISTICS (Note 5)					•		
Turn-On Delay Time	t _{d(ON)}				14		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			32		ns
Turn-Off Delay Time	t _{d(OFF)}				27		
Fall Time	t _f				17		
DRAIN-SOURCE DIODE CHARACTERISTIC	s				•		
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 10 A	T _J = 25°C		0.75	1.1	.,
			T _J = 125°C		0.6		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			47		ns
Charge Time	t _a				23		
Discharge Time	t _b				24		
Reverse Recovery Charge	Q _{RR}				39		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

5. Switching characteristics are independent of operating junction temperatures.

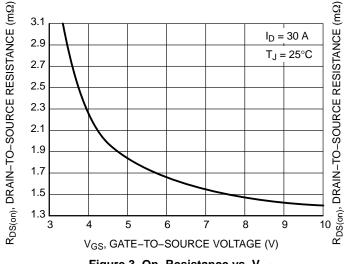
TYPICAL CHARACTERISTICS



250 $V_{DS} = 3 V$ 225 200 ID, DRAIN CURRENT (A) 175 150 125 100 $T_{J} = 150^{\circ}C$ 75 50 $T_{.1} = -55^{\circ}C$ 25 0 1.5 3.5 4.5 VGS, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



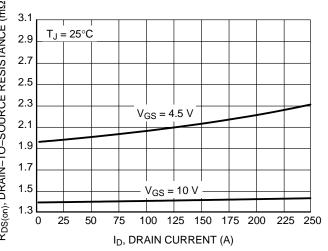
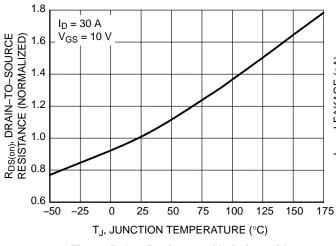


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On-Resistance vs. Drain Current and **Gate Voltage**



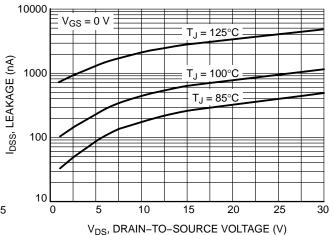


Figure 5. On-Resistance Variation with **Temperature**

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

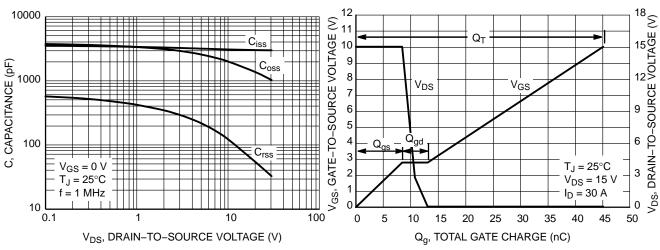


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

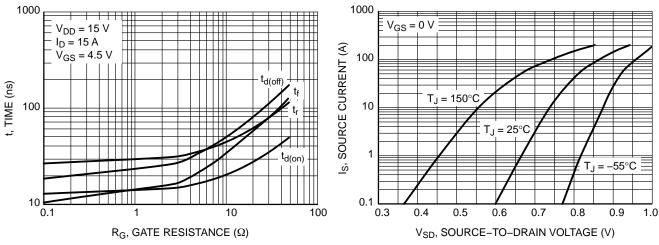


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

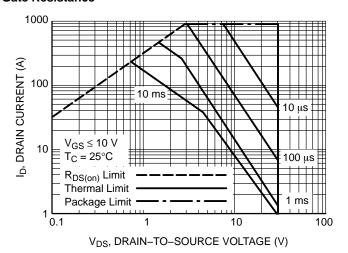


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

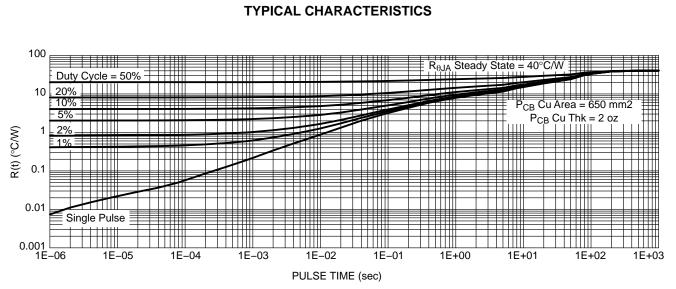


Figure 12. Thermal Impedance (Junction-to-Ambient)

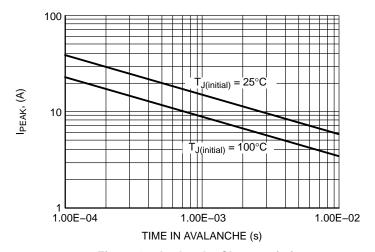
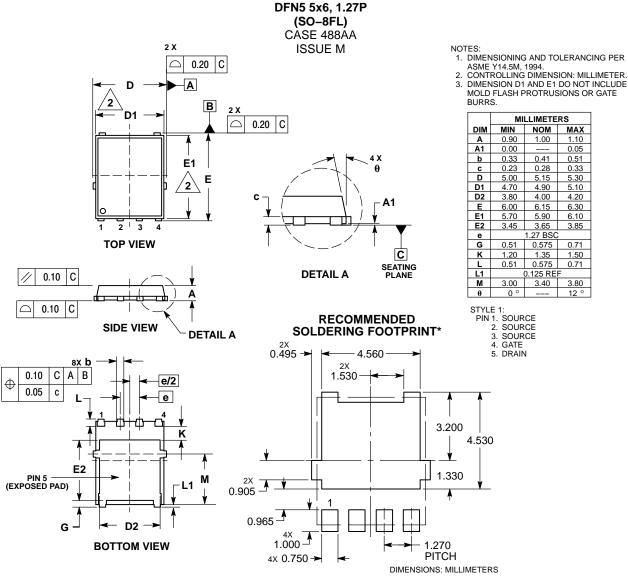


Figure 13. Avalanche Characteristics

PACKAGE DIMENSIONS



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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